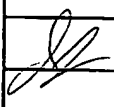


FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 58546.00016	SERIAL NO. New Application
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT OKADA et al	
		10/78/756	
		FILING DATE February 20, 2004	GROUP Not yet assigned

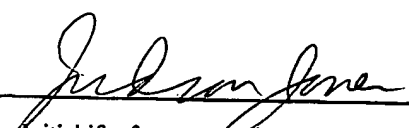
U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

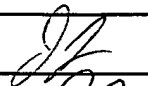
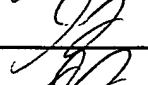
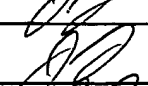
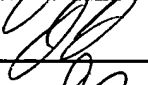

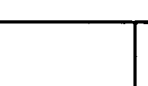
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION		
							YES	NO	PART.
	AG	2001-195130	07/19/01	Japan	6050	3/00			xx
	AH								
	AI								
	AJ								
	AK								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AL	
AM	
AN	
EXAMINER 	DATE CONSIDERED 9/13/2005
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
		58546.00016	10/781,756
		APPLICANT OKADA et al.	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		FILING DATE February 20, 2004	GROUP 3652

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA	2004/0051854 A1	March 18, 2004	Tanaka et al.	355	53	
	AB	2004/0012768 A1	January 22, 2004	Tanaka et al.	355	72	
	AC	2002/0075467 A1	June 20, 2002	Tanaka et al.	355	57	
	AD	6,408,045 B1	June 18, 2002	Matsui et al.	378	34	
	AE	5,815,246	September 29, 1998	Sperling et al.	355	53	
	AF	6,417,914 B1	July 9, 2002	Li	355	75	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
	AG								
	AH								
	AI								
	AJ								
	AK								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
	AM	
	AN	

EXAMINER

DATE CONSIDERED

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